FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. 03500.103123		ATION NO.	
						10/553,660	
				APPLICANT Manabu Komatsu et al.			
				FILING DATE December 22, 2004		ROUP	'43
				U.S. PATENT DOCUMENTS			
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		5,365,563	11/15/94	Kira et al.	378	48	
		6,579,139 B1	06/17/03	Mishima et al.	445	24	
		6,476,215 B1	11/05/02	Okamoto et al.	536	25.3	
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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
	JP	2000-251665	09/14/00	Japan			Abstract
	JP	11-187900	07/13/99	Japan			Abstract
	JP	4-361055	12/14/92	Japan			Abstract
		ОТН	ER DOCUMENT(S	i) (Including Author, Title, Date, Pertinent Pages, Etc.)	ı		
l		Paolo Lazzeri et al Contaminant Quar	., "Use of S _i ntification o	pin-Coated TXRF Reference Samp n Silicon Wafers," 29 <i>Surf. Interfa</i> c	oles for To	F-SIMS Me 08-803 (200	tal)0).

*EVAMINED: Initial if reference considered, whether or not citation is in conformance with MDED 600; Draw line through citation if not in conformance and not considered.	lared Industa see
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered.	ereu. Include cop
of this form with next communication to applicant.	

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/Brian Gordon/

Sheet_1_ of _1_

10/09/2008

EXAMINER